



*SDW*

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/751,159 Confirmation No. 1864  
Applicant : J. Puttappa et al.  
Filed : January 2, 2004  
Title : SPECKLE PATTERN ANALYSIS METHOD AND SYSTEM  
TC/A.U. : 2877  
Examiner : CONNOLLY, Patrick J.  
  
Docket No. : RHV-P0004.01  
Customer No. : 27268

MAIL STOP AMENDMENT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

AMENDMENT

Sir:

In response to the Office Action mailed January 12, 2006, please consider the following:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks** begin on page 6 of this paper.

06/20/2006 FMETEKI1 00000013 10751159

01 FC:2202

175.00 DP